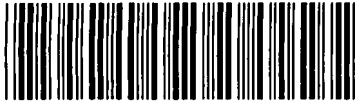


Search Notes

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10/623,320

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

ICHIKAWA ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	8/23/2007	NT
Text search all classes - see search history printout	8/23/2007	NT